



TW

00862.002907

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: )  
Shoshi KATAYAMA )  
Application No.: 09/343,093 )  
Filed: June 30, 1999 )  
For: POSITION DETECTION APPARATUS AND )  
EXPOSURE APPARATUS )  
Examiner: G. J. Stock, Jr.  
Group Art Unit: 2877  
Confirmation No.: 7483  
September 6, 2005

**Mail Stop Amendment**

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

Transmitted herewith is a Request for Reconsideration in the above-identified application.

☒ No additional fee is required.


The fee has been calculated as shown below:

CLAIMS AS AMENDED						
	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NO. PREVIOUSLY PAID FOR	PRESENT EXTRA	RATE	ADDITIONAL FEE
TOTAL CLAIMS	24	MINUS	24	= 0	x \$25 \$50	\$0.00
INDEP. CLAIMS	6	MINUS	6	= 0	x \$100 \$200	\$0.00
Fee for Multiple Dependent claims \$180/\$360						—
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT						\$0.00

☐ °Verified Statement claiming small entity status is enclosed, if not filed previously.

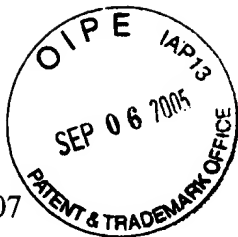
- ☐ A check in the amount of \$\_\_\_\_\_ is enclosed including the additional claims fee.
- ☐ Charge \$\_\_\_\_\_ to Deposit Account No. 06-1205.
- ☒ Any prior general authorization to charge an issue fee under 37 CFR 1.18 to Deposit Account No. 06-1205 is hereby revoked. The Commissioner is hereby authorized to charge any additional fees under 37 CFR 1.16 and 1.17 which may be required during the entire pendency of this application, or to credit any overpayment, to Deposit Account No. 06-1205.
- ☐ A check in the amount of \$\_\_\_\_\_ to cover the fee for a two month extension is enclosed.
- ☐ A check in the amount of \$\_\_\_\_\_ to cover the Information Disclosure Statement fee is enclosed.
- ☒ Applicant's undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should be directed to our address given below.

Respectfully submitted,

  
Attorney for Applicant  
Steven E. Warner  
Registration No. 33,326

FITZPATRICK, CELLA, HARPER & SCINTO  
30 Rockefeller Plaza  
New York, New York 10112-3801  
Facsimile: (212) 218-2200  
SEW/eab

DC\_MAIN 141835v1



00862.002907

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	)	
	:	Examiner: G. J. Stock, Jr.
Shoshi KATAYAMA	)	
	:	Group Art Unit: 2877
Application No.: 09/343,093	)	
	:	Confirmation No.: 7483
Filed: June 30, 1999	)	
	:	
For: POSITION DETECTION	)	
APPARATUS AND EXPOSURE	:	
APPARATUS	)	September 6, 2005

**Mail Stop Amendment**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

REQUEST FOR RECONSIDERATION

Sir:

In response to the Office Action issued June 6, 2005, Applicant requests favorable reconsideration and allowance of the subject application in view of the following remarks.

Claims 27-50 are presented for consideration. Claims 27, 36 and 47-50 are independent.

Applicant requests favorable reconsideration and withdrawal of the rejection set forth in the above-noted Office Action.

Claims 27-50 were rejected under 35 U.S.C. § 102(b) as being anticipated by (*sic* § 103 as being unpatentable over) U.S. Patent No. 5,243,195 to Nishi in view of U.S. Patent No. 4,566,795 to Matsuura et al. This rejection is respectfully traversed.

In one aspect of the present invention, independent claim 27 recites an apparatus for determining a position of a mark on an object placed on a stage. The apparatus includes, among

other features, a measurement system which measures a position of the stage plural times during an accumulation period of an image sensor, and an arithmetic section which calculates the position of the mark based on the image data obtained by the image sensing system and data of plural positions of the stage measured by the measurement system during the accumulation period of the image sensor with respect to the image data.

In another aspect of the present invention, independent claim 36 recites, among other features, first and second measurement systems and a calculation section. The calculation section recited in this claim performs a calculation along the lines of the arithmetic section of the present invention recited in independent claim 27.

In yet another aspect of the of the present invention, independent claim 47 recites a method for determining a position of a mark on an object placed on a stage. Claim 47 recites, among other features, first and second measuring steps, and a calculating step, which performs a calculation along the lines performed by the arithmetic section of the present invention recited in independent claim 28.

In still other aspects of the present invention, independent claim 48 recites a method adapted for an exposure apparatus having a stage on which a substrate is placed, and a lens section which projects a pattern onto the substrate, independent claim 49 recites a method of manufacturing a device, using an exposure apparatus having a stage on which a substrate is placed, and a lens section which projects a pattern onto the substrate, and independent claim 50 recites an apparatus for determining a position of a mark on an object placed on a stage. These claims recite similar measurement and calculation elements and steps as those recited in the independent claims discussed above.